

# Search Notes



Application/Control No.

10/757,782

Examiner

José V. Chen

Applicant(s)/Patent under  
Reexamination

WUNSH ET AL.

Art Unit

3837

## SEARCHED

Class	Subclass	Date	Examiner
108	25 24 27 12 14 13 40 161	9/14/15	JLC
206	769 770 326		
<del>ADACON 5/19/16, JLC</del>			
<del>ADACON 9/12/15, JLC</del>			
<del>ADACON 2/20/17, JLC</del>			

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Long Back Gr. For Post-Act	9/20/15	JLC
<del>ADACON</del>	<del>9/19/15</del>	<del>JLC</del>
<del>ADACON</del>	<del>2/20/17</del>	<del>JLC</del>